

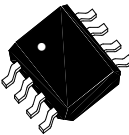


N-Channel Enhancement-Mode MOSFET (30V, 10A)

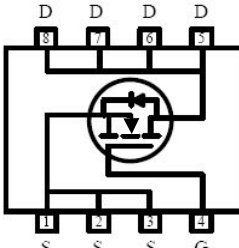
PRODUCT SUMMARY		
V_{DS}	I_D	$R_{DS(on)}$ (m-ohm) Max
30V	10A	13.5 @ $V_{GS} = 10V, I_D=10A$
		20 @ $V_{GS} = 4.5V, I_D=5A$

Features

- Advanced Trench Process Technology
- High Density Cell Design for Ultra Low On-Resistance
- Lead free product is acquired
- Surface mount Package



SOP-8



Pin 1 / 2 / 3: Source
Pin 4: Gate
Pin 5 / 6 / 7 / 8: Drain

Absolute Maximum Ratings ($T_A=25^{\circ}C$, unless otherwise noted)

Symbol	Parameter	Ratings	Units
V_{DS}	Drain-Source Voltage	30	V
V_{GS}	Gate-Source Voltage	± 20	V
I_D	Drain Current @ $T_A=25^{\circ}C$	10	A
I_{DM}	Drain Current (Pulsed) ^a	50	A
P_D	Total Power Dissipation @ $T_A=25^{\circ}C$	2.5	W
T_j, T_{stg}	Operating Junction and Storage Temperature Range	-55 to +150	$^{\circ}C$
$R_{\theta JA}$	Thermal Resistance Junction to Ambient	50	$^{\circ}C/W$

a: Repetitive Rating: Pulse width limited by the maximum junction temperature.
b: 1-in² 2oz Cu PCB board



Electrical Characteristics ($T_A=25^{\circ}\text{C}$, unless otherwise noted)

Symbol	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
• Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	30	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=24V, V_{GS}=0V$	-	-	50	nA
I_{GSS}		Gate-Body Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	
• On Characteristics^c						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	1	-	2.5	V
$R_{DS(on)}$	Drain-Source On-State Resistance	$V_{GS}=10V, I_D=10A$	-	-	13.5	m Ω
		$V_{GS}=4.5V, I_D=5A$	-	-	20	
g_{FS}	Forward Transconductance	$V_{DS}=10V, I_D=9A$	-	9	-	S
• Dynamic Characteristics^d						
C_{iss}	Input Capacitance	$V_{DS}=25V, V_{GS}=0V, f=1\text{MHz}$	-	710	1350	pF
C_{oss}	Output Capacitance		-	155	-	
C_{rss}	Reverse Transfer Capacitance		-	145	-	
R_g	Gate resistance	$V_{DS}=0V, V_{GS}=0V, f=1\text{MHz}$	-	2	3	Ω
• Switching Characteristics^d						
Q_g	Total Gate Charge	$V_{DS}=20V, I_D=9A, V_{GS}=4.5V$	-	8	-	nC
Q_{gs}	Gate-Source Charge		-	3.3	-	
Q_{gd}	Gate-Drain Charge		-	2.7	-	
$t_{d(on)}$	Turn-on Delay Time	$V_{GS}=10V, V_{DS}=15V, I_D=9A, R_L=15\Omega, R_{GEN}=3.3\Omega$	-	7	-	nS
t_r	Turn-on Rise Time		-	7	-	
$t_{d(off)}$	Turn-off Delay Time		-	22	-	
t_f	Turn-off Fall Time		-	7	-	
t_{rr}	Body Diode Reverse Recovery Time	$I_F=9A, di/dt=100A/\mu S$	-	24	-	nS
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=9A, di/dt=100A/\mu S$	-	14	-	nC
• Drain-Source Diode Characteristics						
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS}=0V, I_S=2.1A$	-	-	1.2	V

Note: Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$



Characteristics Curve

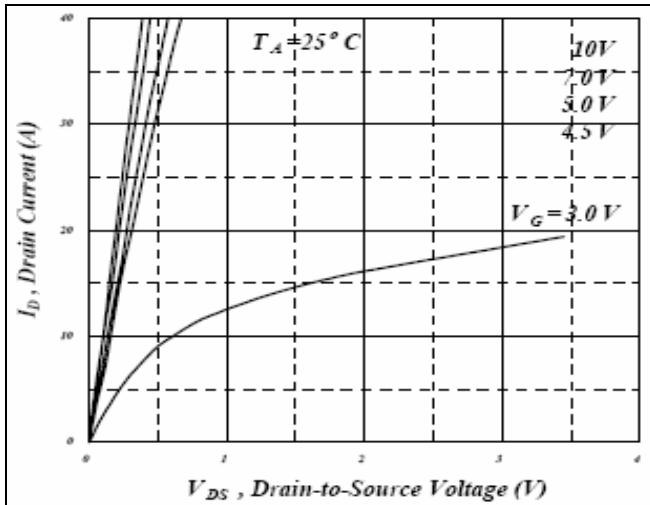


Fig 1. Typical Output Characteristics

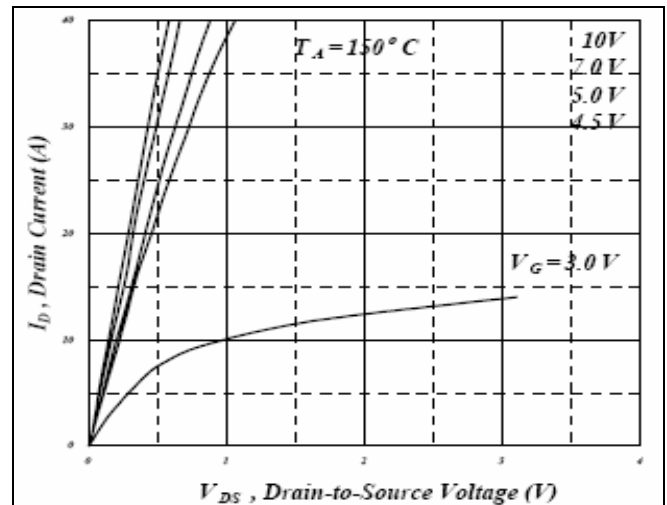


Fig 2. Typical Output Characteristics

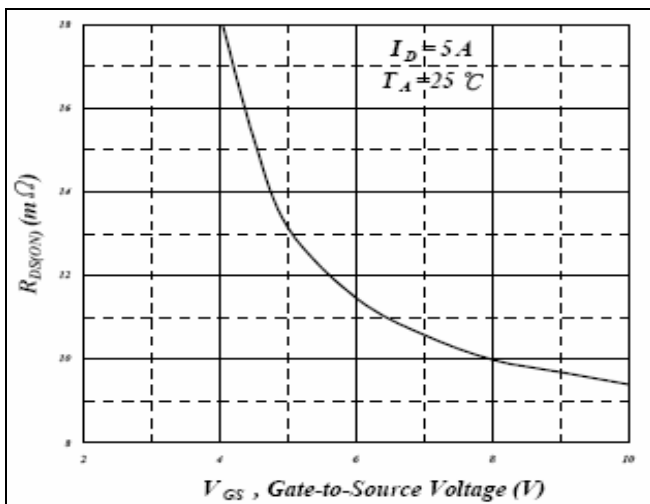


Fig 3. On-Resistance v.s. Gate Voltage

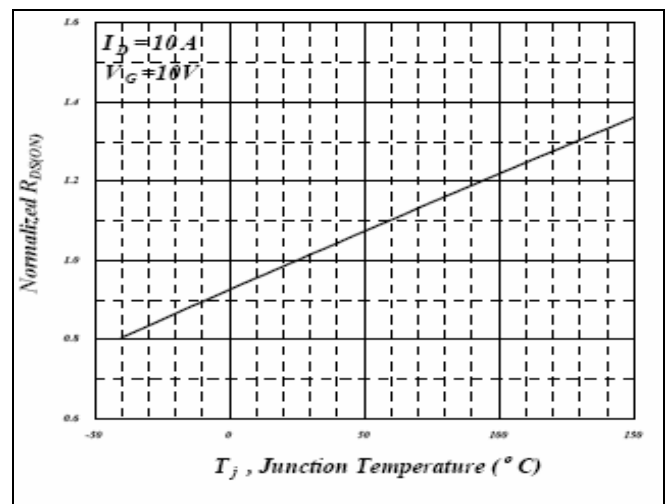


Fig 4. Normalized On-Resistance v.s. Junction Temperature

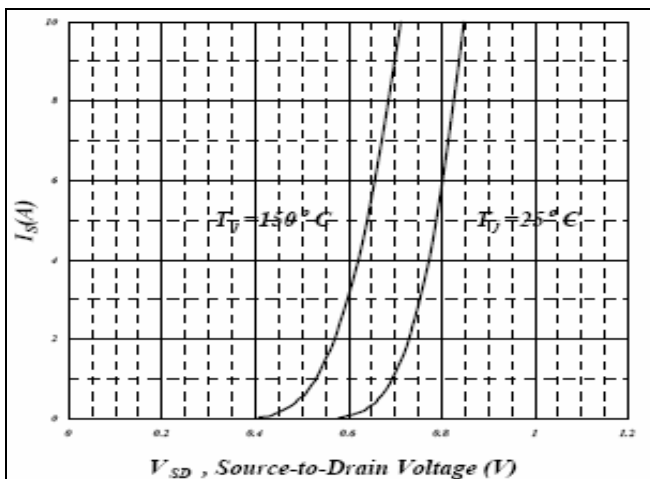


Fig 5. Forward Characteristic of Reverse Diode

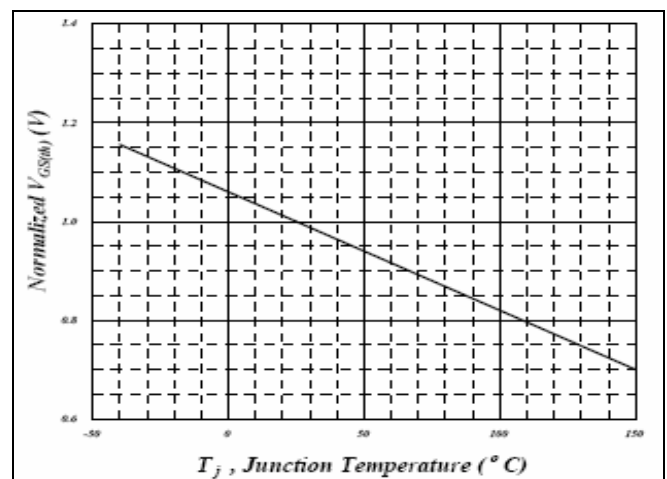


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

Characteristics Curve

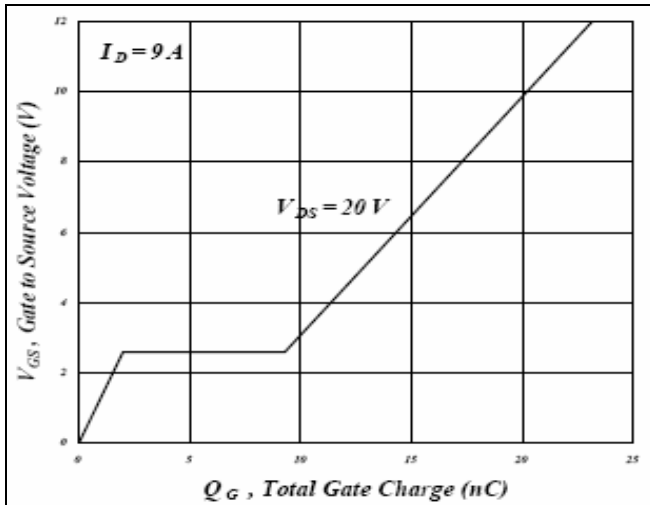


Fig 7. Gate Charge Characteristics

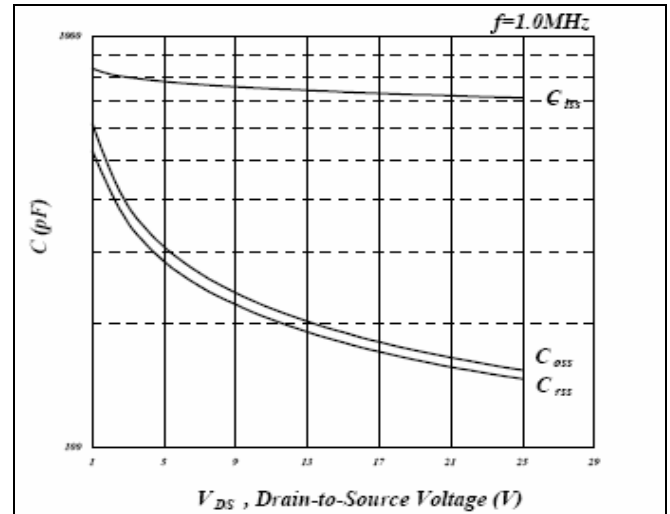


Fig 8. Typical Capacitance Characteristics

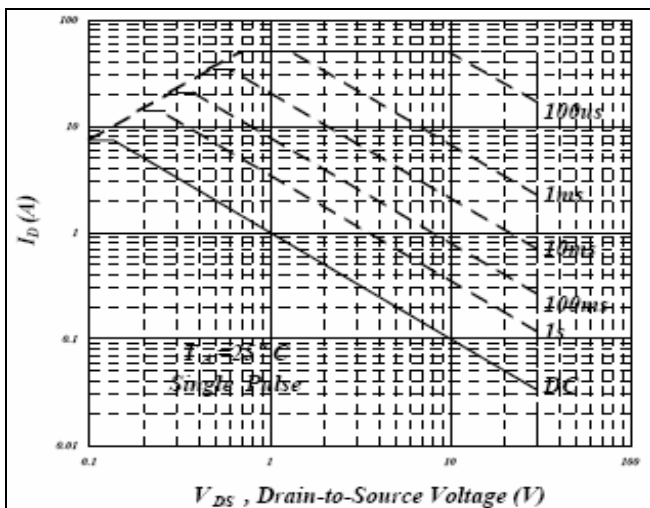


Fig 9. Maximum Safe Operating Area

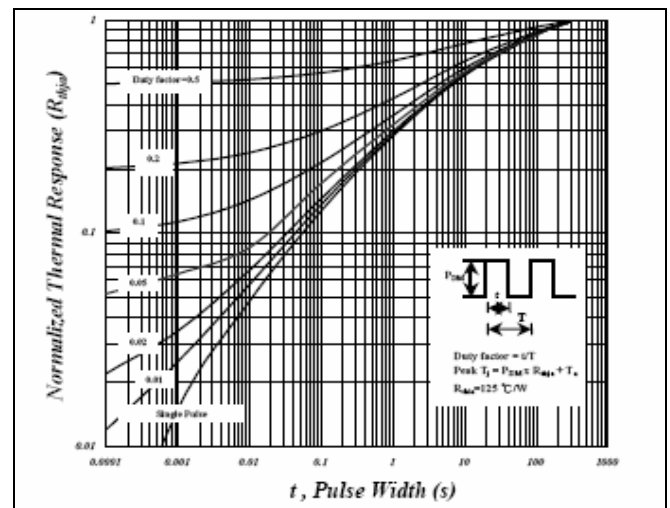


Fig 10. Effective Transient Thermal Impedance

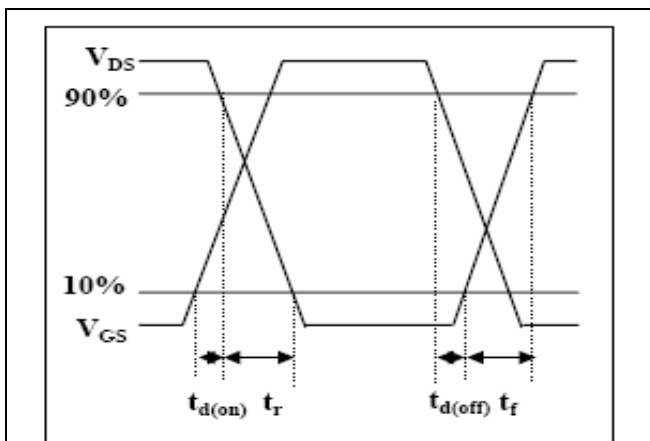


Fig 11. Switching Time Waveform

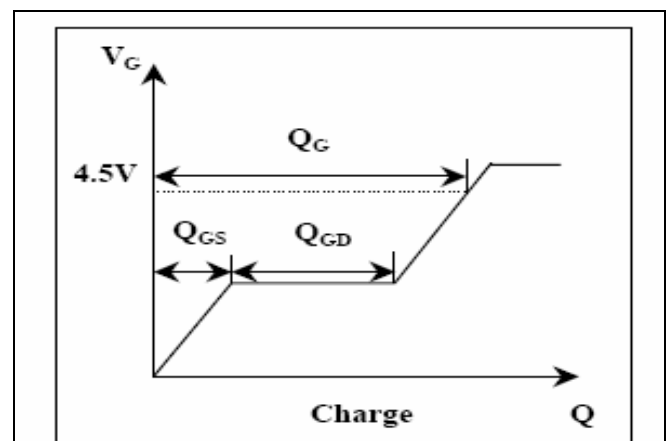


Fig 12. Gate Charge Waveform